Guest editorial

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Scientific computing in electrical engineering (SCEE 2018)

The 12th International Conference on *Scientific Computing in Electrical Engineering* (SCEE) was organized by the Group of Applied Mathematics at the University of Catania, Italy, jointly with the Interdepartmental Center of Mathematics for Technology "A.M. Anile" (CIMAT). It was held in the period 23-27 September, 2019 in Taormina, Italy, a charming town on a cliff by the sea on the east coast of the island of Sicily, with a mythical atmosphere spread all around which has enchanted visitors from all over the world for years and years.

The SCEE series of conferences has an interdisciplinary focus and provides a platform for sharing the results of the latest scientific research about modelling and numerical simulation related to electrical engineering in a broad sense. The main topics of the conference concern computational electromagnetics, circuit and device modelling and simulation, coupled problems and multi–scale approaches in space and time, mathematical and computational methods including uncertainty quantification, model order reduction, industrial applications. More information can be found on the web site www.sceeconferences.org/posts.

That in Taormina was the 12th edition (for details see the web page https://scee2018.icas. xyz) after the conference series started as a national meeting in 1997 in Darmstadt, Germany. The other previous editions were held in Wolfgang, Austria (2016), Wuppertal, Germany (2014), Zurich, Switzerland (2012), Toulouse, France (2010), Espoo, Finland (2008), Sinaia, Romania (2006), Capo d'Orlando, Italy (2004), Eindhoven, Netherlands (2002), Warnemünde, Germany (2000), Berlin, Germany (1998).

This special issue contains a selection of the contributions to SCEE 2018, after a regular peer-review process.

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